Application/Control No. 10/797,779 Applicant(s)/Patent Under Reexamination ZENG, KEJUN Examiner Lynne Edmondson Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A.	US-5,803,344	09-1998	Stankavich et al.	228/180.22
*	В	US-6,214,636	04-2001	Sawayama et al.	438/57
*	C.	US-3,855,679	12-1974	Schmatz, Duane J.	428/643
*	D	US-2001/0028109	10-2001	Shimizu et al.	257/737
*	Е	US-6,300,578	10-2001	Hoffmeyer et al.	174/263
*	F	US-6,142,363	11-2000	Tanahashi et al.	228/224
*	G	US-6,576,971	06-2003	Kimoto et al.	257/467
*	Н	US-6,050,480	04-2000	Taguchi et al.	228/248.1
*		_US-6,300,578	10-2001	Hoffmeyer et al.	174/263
*	J	US-6,902,102	06-2005	Tanabe et al.	228/260
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP-2002-086294-A	03-2002	Japan	Tanaka et al.	
*	0	JP2001-113387-A	04-2001	Japan	Tanaka et al.	
	Р					
	σ					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	W	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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